Group Art Unit:

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Hiroyuki FUKITA et al.

Serial No.: New Application

Filed: March 21, 2002 Examiner:

For: METHOD FOR FINE PATTERN FORMATION

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents Washington, D.C. 20231

Sir:

Pursuant to 37 C.F.R. §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached Form PTO-1449. Copies of each of the references listed on Form PTO-1449 are attached.

Also enclosed is a copy of a International Search Report bearing a mailing date of January 15, 2002, and the U.S. PTO is directed thereto for a concise statement of possible relevance of the references cited therein.

The above information is presented so that the Patent and Trademark Office may, in the first instance, determine any materiality thereof to the claimed invention. See 37 C.F.R. 1.104(a) and 1.106(b) concerning the PTO duty to consider and use

any such information. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that these references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

Respectfully submitted,

Charles A. Wendel

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Date

CAW/ch

Attorney Docket No.: DAIN:673

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(rev. 4/96)

| Sheet 1 of 1 | | | | JC13 Ra | C'd PCT/PTO | 0886 21 MAI | 2002 |
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| FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) | | | ATTY DOCKET NO. DAIN:673 SERIAL NO. New Application | | | | |
| | | | APPLICANT Hiroyuki FUKITA et al. | | | | |
| | | | FILING DATE March 21, 2002 | | GROUP | | |
| U.S. PATENT DOCUMENTS | | | | | | | |
| *EXAMINER INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE | |
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| FOREIGN PATENT DOCUMENTS | | | | | | | |
| | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION NO YES | |
| V | 2000-167463 | 6/20/00 | Japan (w/Abstract) | | | х | |
| √ | 9-57981 / | 3/4/97 | Japan (w/Abstract) | | | х | |
| | 8-071477 | 3/19/96 | Japan (w/Abstract) | | | х | |
| | 11-239748 / | 9/7/99 | Japan (w/Abstract) | | | х | |
| J | 2000-189873 | 7/11/00 | Japan (w/Abstract) | | <u> </u> | х | |
| | EP 0 985 534 A1 | 3/15/00 | EPO | | l | | |
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applica-